

PROCESSES AND PROCESS CONTROL (INTRODUCTION)

PWA ASSEMBLY PROCESSES

BY

SCOTT DAHNE

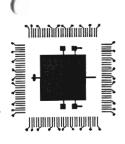
WESTINGHOUSE ELECTRIC CORPORATION ELECTRONIC SYSTEMS GROUP

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GENERAL ELECTRIC

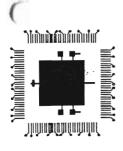
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MARTIN MARIETTA
89 NEPCON EAST/SD01



PROCESSES AND PROCESS CONTROL (GOALS)

- DEVELOP PROCESS FOR ECONOMICAL AND RELIABLE MANUFACTURING OF VHSIC PWAs
- ACHIEVE 1000 -55 °C TO +125 °C FAILURE FREE THERMAL CYCLES



PROCESSES AND PROCESS CONTROL (THERMAL CYCLES)

■ RANGE: -55 C TO +125 C

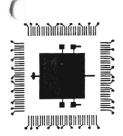
• RAMP RATE: 5°C PER MINUTE

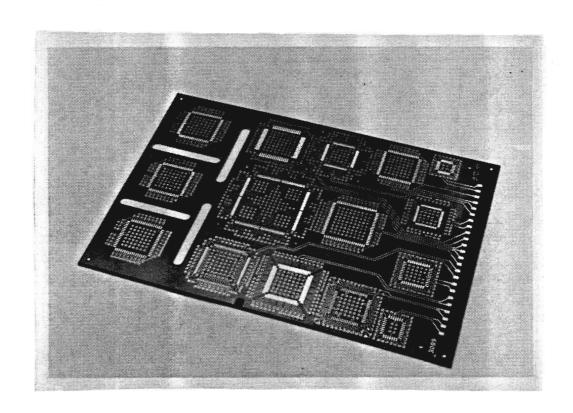
DWELL AT TEMPERATURE: 24 MINUTES

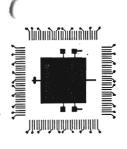
TOTAL CYCLE: 2 HOURS

MONITORING: EVERY 2 MINUTES, DC

 FAILURE CRITERION: 10 X NOMINAL RESISTANCE



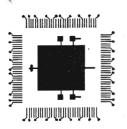




PROCESSES AND PROCESS CONTROL (DISCLAIMER)

THE MATERIALS AND EQUIPMENT SPECIFIED IN THE FOLLOWING SLIDES DOES NOT CONSTITUTE AN ENDORSEMENT FOR THOSE PRODUCTS.

THERE ARE MANY ALTERNATIVE PRODUCTS AVAILABLE.



PROCESSES AND PROCESS CONTROL (PROCESS VARIABLES ADDRESSED)

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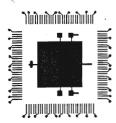
CONDITION "0" CONDITION "1"

LEADLESS FILLET	NOMINAL	BULBOUS
LEADED VOLUME	MINIMUM	ADDITIONAL
LEADLESS HEIGHT	4-5 MIL	8-10 MILS
LEAD STRESS	NO STRESS	STRESSED
SOLDER ALLOY	63/37 Sn/Pb	50/50 Sn/Pb
PRETIN ALLOY	63/37 Sn/Pb	50/50 Sn/Pb
SOLDER FORM	PASTE	PREFORMS
PWB SURFACE FINISH	BARE COPPER	NICKEL
PWB MATERIAL	QUATREX/KEVLAR	POLYIMIDE/E-GLASS

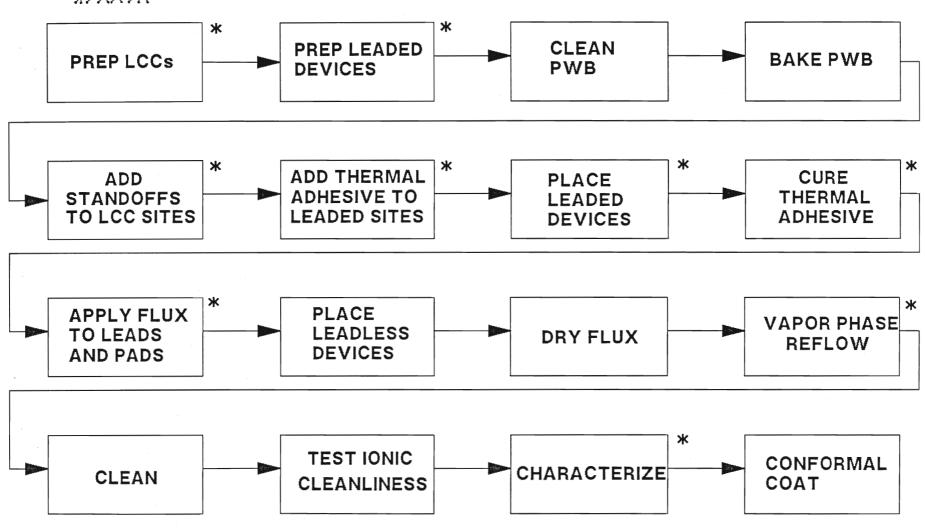
GENERAL ELECTRIC

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PROCESSES AND PROCESS CONTROL (PROCESS FLOWCHART - PREFORMS)

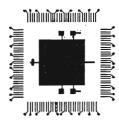


GENERAL ELECTRIC

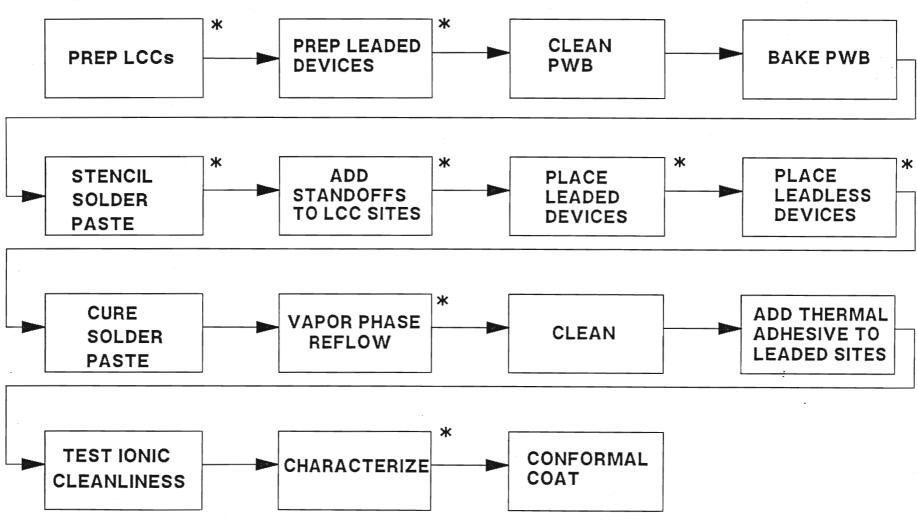
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* DESIGNATES ADSP/MT AREA OF CONCENTRATION



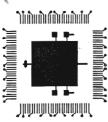
PROCESSES AND PROCESS CONTROL (PROCESS FLOWCHART - STENCILS)



GENERAL ELECTRIC

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PROCESSES AND PROCESS CONTROL (MATERIALS)

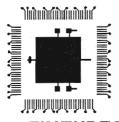
- SOLDER
 - SOLDER INGOTS 63/37 Sn/Pb (ALPHA METALS)
 - PREFORMS 63/37 Sn/Pb (ALPHA METALS)
 - ◆ SOLDER PASTE (ALPHA) RMA 390DH3, 90% METALS, 650,000 CPS, -325/+500 MESH
 - SOLDERQUIK PREFORM (RAYCHEM)
- CLEANING SOLVENT
 - DOW PRELETE
 - ALPHA 565
 - DUPONT FREON TMS
- ADHESNE
 - ABLEFILM 561KTW (THERMAL ADHESIVE)
 - EPO-TEK 115-SMT (THERMAL ADHESIVE)
 - DYMAX 20199 (UV CUREABLE ADHESIVE)
- FLUX
 - ALPHA 611
 - KESTER 185
- VAPOR PHASE FLUID
 - FC5312 (3M)
 - FC5311 (3M)
 - FC70 (3M)
 - FREON TF (DUPONT)

- CONFORMAL COAT
 - HUMISEAL 1B31 (ACRYLIC)
 - ◆ CONAP CE-1155 (POLYURETHANE)
 - DOW 3140 (SILICONE)

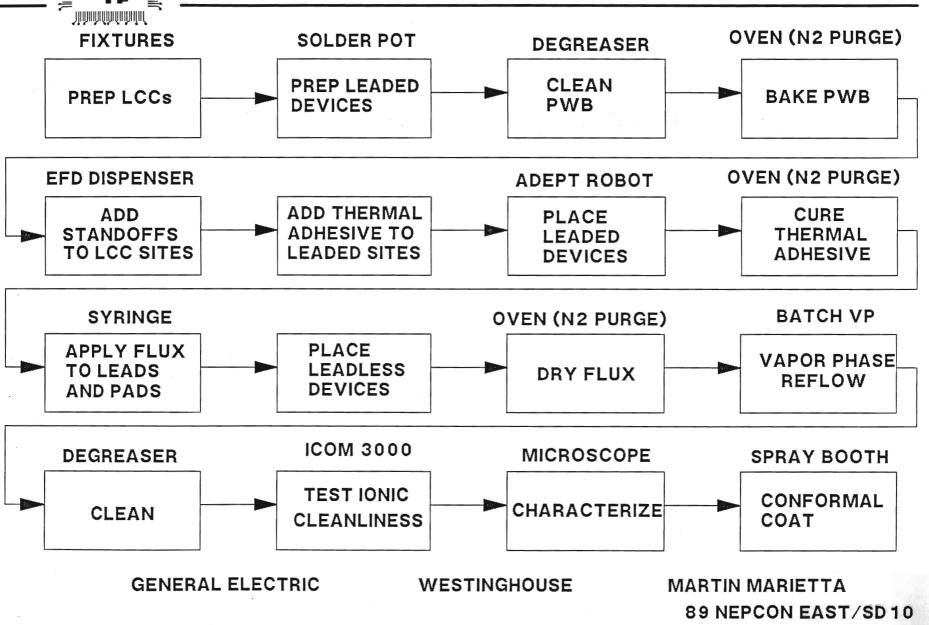
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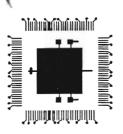
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MARTIN MARIETTA 89 NEPCON EAST/SD09



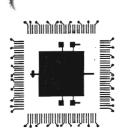
PROCESSES AND PROCESS CONTROL (EQUIPMENT FLOWCHART)





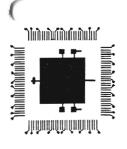
PROCESSES AND PROCESS CONTROL (MATERIALS)

MATERIALS



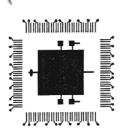
PROCESSES AND PROCESS CONTROL (SOLDER PASTE)

- 63/37 Sn/Pb ALLOY
- RMA FLUX
- ◆ FINE MESH SIZE (-200/+325 TO -325/+500 MESH)
- HIGH METALS CONTENT (90% MINIMUM)
- MINIMUM SLUMPING (10% MAXIMUM)
- VISCOSITY OF 650,000 TO 900,000 CPS
- PASTE MUST BE BAKED OUT PRIOR TO REFLOW
- PROPER CONTROL OF UNUSED AND USED PASTE



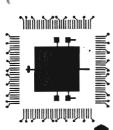
PROCESSES AND PROCESS CONTROL (PREFORMS)

- SPHERICAL PREFORMS
 - 63/37 Sn/Pb ALLOY
 - .021" AND .031" DIAMETER
- FLUXLESS ATTACHMENT TO LCCs WITH SPECIAL FIXTURE
- ALL PARTS PREPARED PRIOR TO ASSEMBLY OF PWB



PROCESSES AND PROCESS CONTROL (FLUX)

- RMA FLUX PER MIL-F-14256
- SOLDER PASTE USES SAME FLUX FOR COMPATIBILITY
- USE THERMOGRAVIMETRIC ANALYSIS (TGA) TO OPTIMIZE PROCESS TO PARTICULAR FLUX USED
- MUST BE CORRECTLY DRIED TO MINIMIZE VOLATIZATION
- DO NOT OVER-APPLY



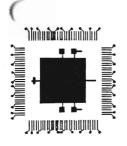
PROCESSES AND PROCESS CONTROL (ADHESIVES)

- THERMAL ADHESIVE
 - ABLEFILM 561KTW
 - 8-12 MILS THICK (DEPENDENT ON LEAD FORMING)
 - CUT TO SIZE FOR EACH PART
 - EPO-TEK 115-SMT
 - APPLIED FROM BACK SIDE OF PWB
 - CAN BE APPLIED BY AUTOMATIC DISPENSING SYSTEM
- LCC STANDOFF ADHESIVE
 - DYMAX 20199
 - UV CUREABLE
 - CAN BE APPLIED BY AUTOMATIC DISPENSING SYSTEM

GENERAL ELECTRIC

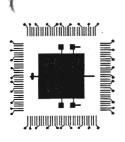
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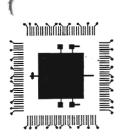
PROCESSES AND PROCESS CONTROL (REFLOW FLUIDS)

- PRIMARY FLUID
 - 3M FC-5312, FC-5311, FC-70
 - 419°F (215°C) BOILING POINT
 - LOWER PFIB AND HF GENERATION
- SECONDARY FLUID
 - DUPONT FREON TF
 - 185°F (85°C) TO 215°F (102°C) BOILING POINT



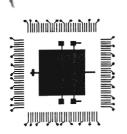
PROCESSES AND PROCESS CONTROL (CLEANING SOLVENTS)

- DOW PRELETE
 - 167°F (75°C) BOILING POINT
- FREON TMS
 - 104°F (40°C) BOILING POINT
- ALPHA 565
 - 165°F (74°C) BOILING POINT
- REPLACE OR DISTILL FLUID WHEN DIRTY



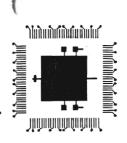
PROCESSES AND PROCESS CONTROL (ASSEMBLY PROCESSES)

ASSEMBLY PROCESSES



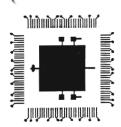
PROCESSES AND PROCESS CONTROL (ASSEMBLY PROCESSES)

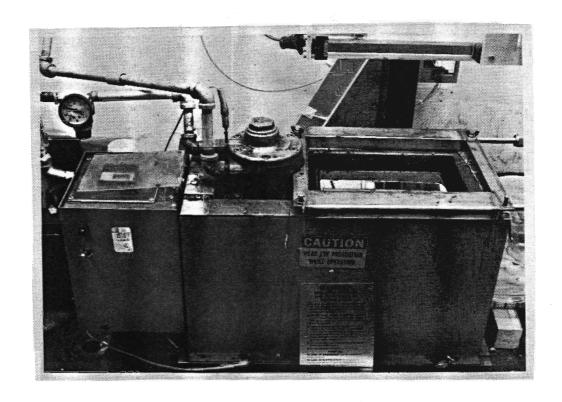
COMPONENT PREPARATION

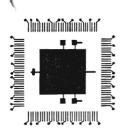


PROCESSES AND PROCESS CONTROL (PRETINNING)

- DYNAMIC (FLOWING) SOLDER POT
 - 500°F +- 5°F TEMPERATURE
- DIP TO WASH AWAY ALL GOLD
- MAINTAIN POT PER WS6536
- INSURE UNIFORM LEAD/CASTELLATION COVERAGE
- NITROGEN BLANKET MAY BE USED
 - ELIMINATES NEED FOR FLUX

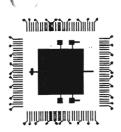


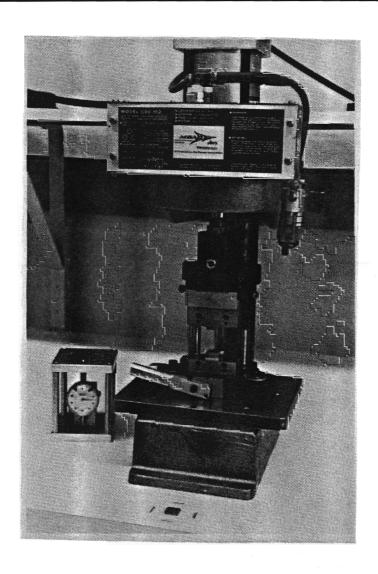




PROCESSES AND PROCESS CONTROL (LEAD FORMING)

- FORM LEADS 9 +- 2 MILS BELOW PACKAGE
 - DEPENDENT UPON THERMAL ADHESIVE HEIGHT USED
- MAINTAIN +-2 MILS COPLANARITY ACROSS LEADS
- CUT OFF CORNERS OF TIE BARS PRIOR TO FORMING
 - ELIMINATES SKEWING OF LEADS DURING FORMING
- HARD TOOLED DIES ELIMINATE NEED FOR ADJUSTMENTS
- CERTIFY ALL DIES !!!

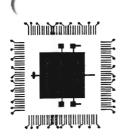


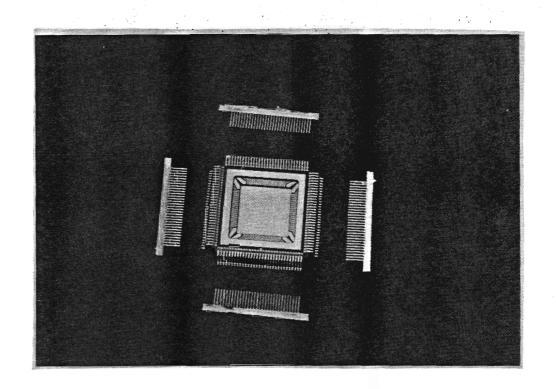


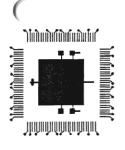
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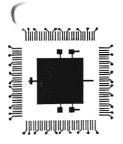


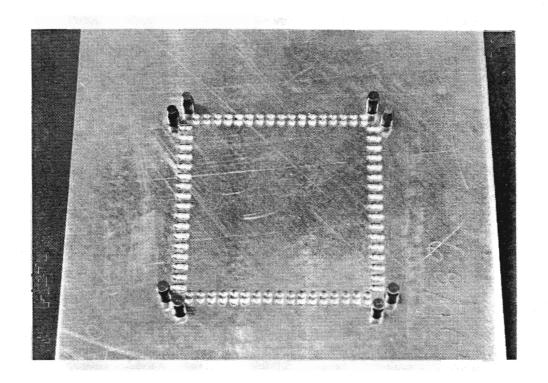


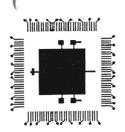


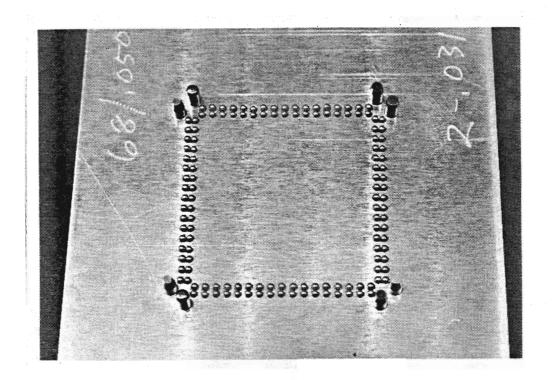
PROCESSES AND PROCESS CONTROL (PREFORMS)

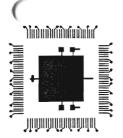
- SPHERICAL PREFORMS
 - 63/37 Sn/Pb ALLOY
 - .021" AND .031" DIAMETER
- FLUXLESS ATTACHMENT TO LCCs WITH SPECIAL FIXTURE
- ALL PARTS PREPARED PRIOR TO ASSEMBLY OF PWB

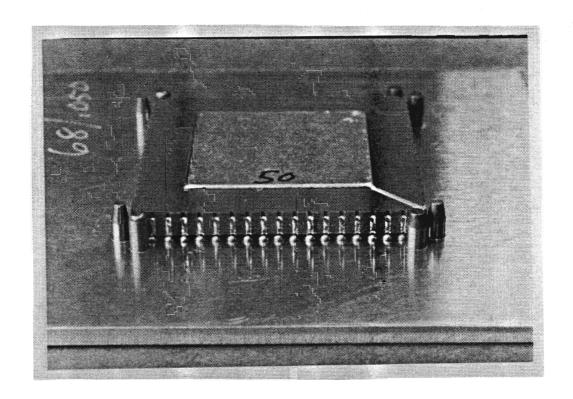








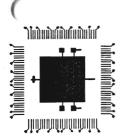


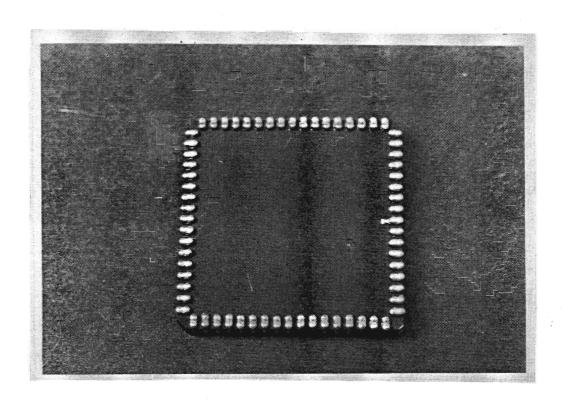


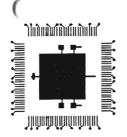
GENERAL ELECTRIC

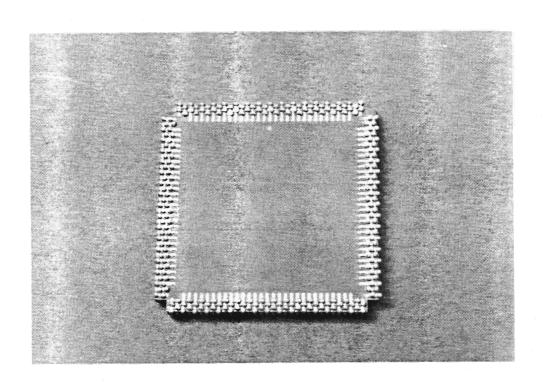
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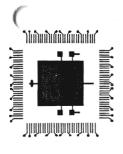
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89 NEPCON EAST/SD28







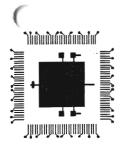




PROCESSES AND PROCESS CONTROL (PREFORMS)

ADVANTAGES

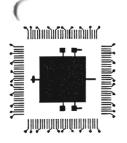
- PRECISE JOINT VOLUMES ARE OBTAINED
- IDENTICAL JOINT TO JOINT GEOMETRY
- THEORETICAL AND ACTUAL VOLUMES
 CAN BE MATCHED
- JOINTS ARE COSMETICALLY SUPERIOR
- JOINTS TEND TO HAVE LESS VOIDS



PROCESSES AND PROCESS CONTROL (PREFORMS)

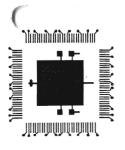
DISADVANTAGES

- PROCESS IS MANUAL IN NATURE AND THUS VERY TIME CONSUMING
- TOOLING IS NOT YET PRODUCTION ORIENTED



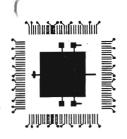
PROCESSES AND PROCESS CONTROL (ASSEMBLY PROCESSES)

PWB PREPARATION



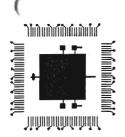
PROCESSES AND PROCESS CONTROL (THICK SOLDER PLATE)

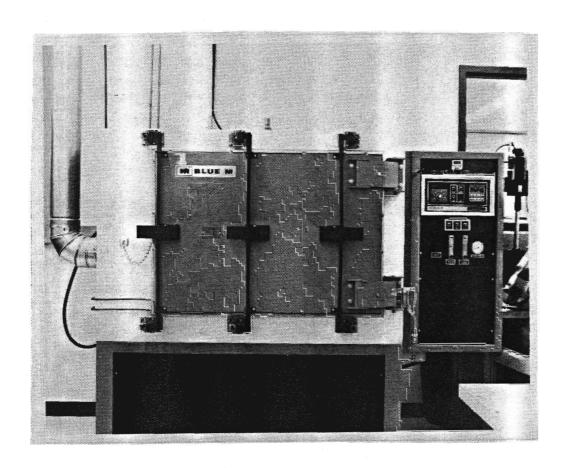
- TIN RANGE 60-66%
- Sn/Pb THICKNESS 2.5 3.5 MILS AS PLATED
 - VERIFY BY CROSS-SECTION OR PROFILOMETER
- VENDOR
 - NORTH AMERICAN PRINTED CIRCUITS

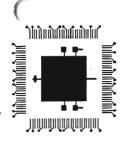


PROCESSES AND PROCESS CONTROL (MOISTURE BAKE-OUT)

- MANY PWB MATERIALS ARE HYGROSCOPIC
- BAKE TO REMOVE MOISTURE
- USE THERMOGRAVIMETRIC ANALYSIS (TGA) TO OPTIMIZE BAKE OUT TIME/TEMPERATURE
- NITROGEN PURGED OVEN TO PREVENT OXIDATION OF SURFACES
- STORE IN NITROGEN FOLLOWING THIS OPERATION
 - **KEEP IN NITROGEN UNTIL AFTER REFLOW**

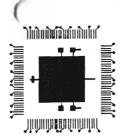


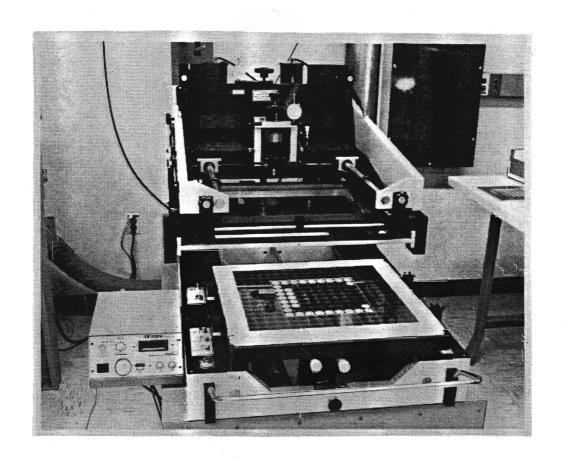


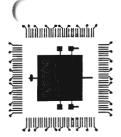


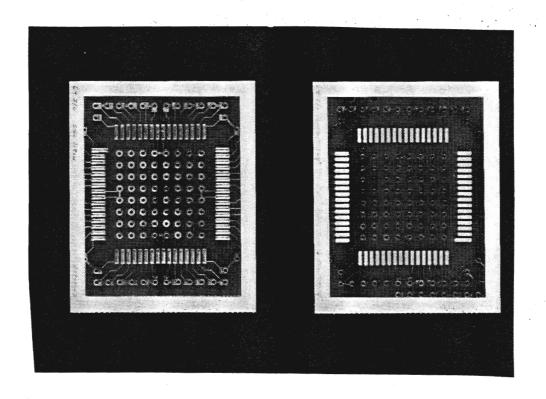
PROCESSES AND PROCESS CONTROL (STENCIL PRINTING)

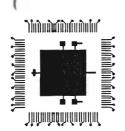
- TIGHT FABRICATION TOLERANCES ON STENCILS (+-2 MILS)
- ON-CONTACT PRINTING
- BARE PWB OR <2 MILS OF SOLDER MASK
- SQUEEGEE PRESSURE 5-10 POUNDS
- SQUEEGEE SPEED 0.5 1.5 INCHES/SECOND
- SQUEEGEE DUROMETER 80 90 SHORE A
- 8 MIL STENCIL FOR 20-25 MIL PITCH
- 12 MIL STENCIL FOR 40-50 MIL PITCH

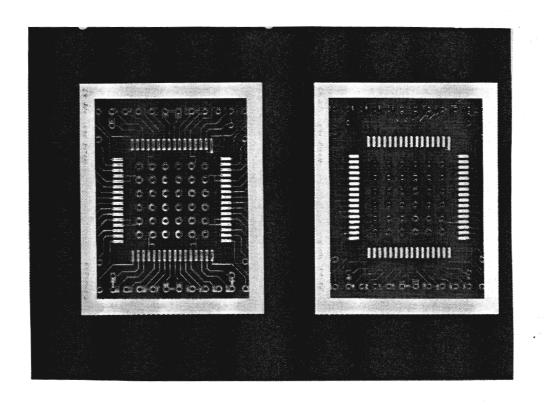


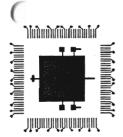


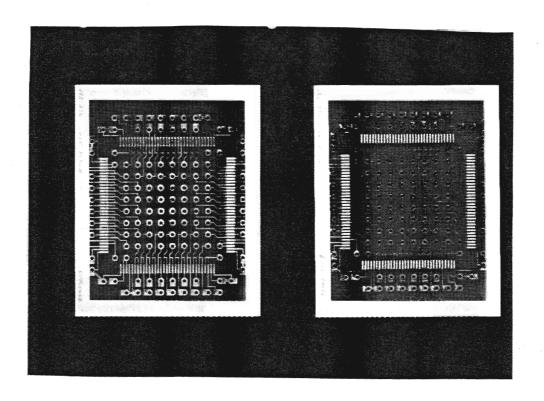


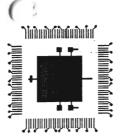


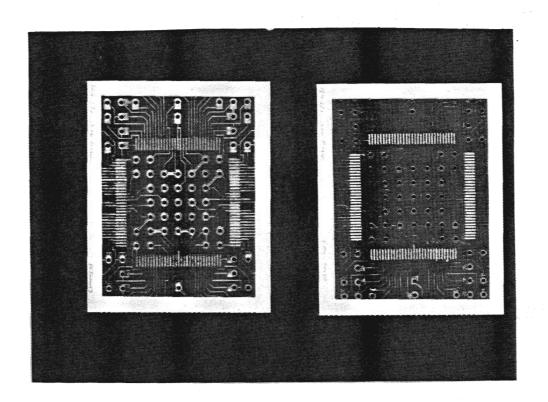


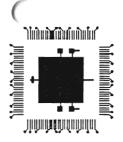






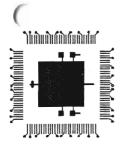






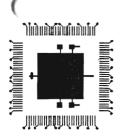
PROCESSES AND PROCESS CONTROL (ASSEMBLY PROCESSES)

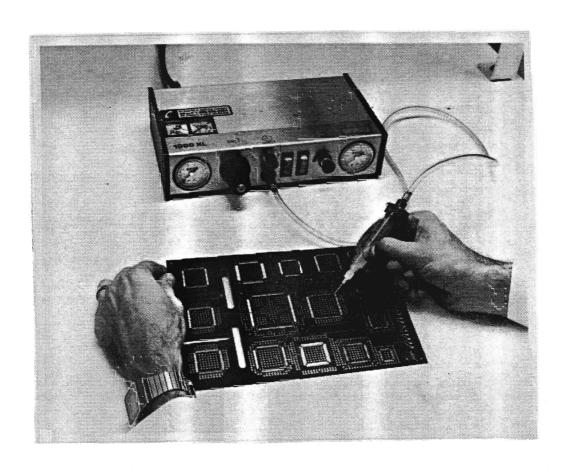
ADHESIVES

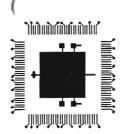


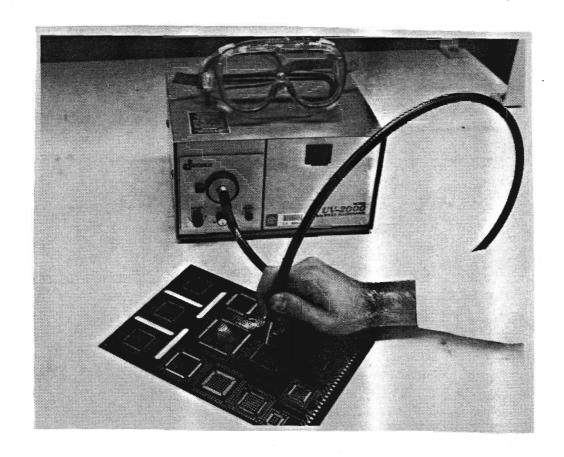
PROCESSES AND PROCESS CONTROL (LCC STANDOFF ADHESIVE)

- EFD SEMI-AUTOMATIC DISPENSING SYSTEM
 - 12 PSI
 - 0.2 SECONDS
 - .024" NEEDLE CUT TO 0.5" LENGTH
- ADHESIVE SHOULD BE AT ROOM TEMPERATURE
- FORM DOT ON TIP OF NEEDLE
- HOLD NEEDLE AT 45 DEGREE ANGLE
- ALLOW CAPILLARY ACTION TO TRANSFER DOT TO PWB SURFACE
- CURE FOR 2-3 SECONDS UNDER 300-350nm UV LAMP





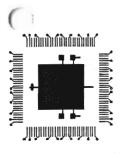




GENERAL ELECTRIC

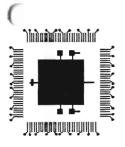
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PROCESSES AND PROCESS CONTROL (THERMAL ADHESIVE)

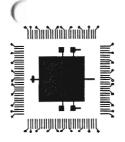
- CUT TO A SIZE RELATIVE TO AMOUNT OF PRESSURE APPLIED DURING CURE
- CENTER PRECUT PIECE BENEATH EACH PART FOR EVEN FLOW
- FABRIC SIDE AGAINST PWB TO MINIMIZE CREEP DURING CURE



PROCESSES AND PROCESS CONTROL (LEADED THERMAL ADHESIVE)

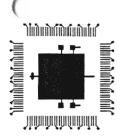
LEADED DEVICE	SIZE OF UNCURED ADHESIVE
64 I/O 40 MIL	.375" X .375"
64 I/O 50 MIL	.500" X .500"
124 I/O 20 MIL	.375" X .375"
132 I/O 25 MIL	.375" X .375"
256 I/O 20 MIL	.875" X .875"

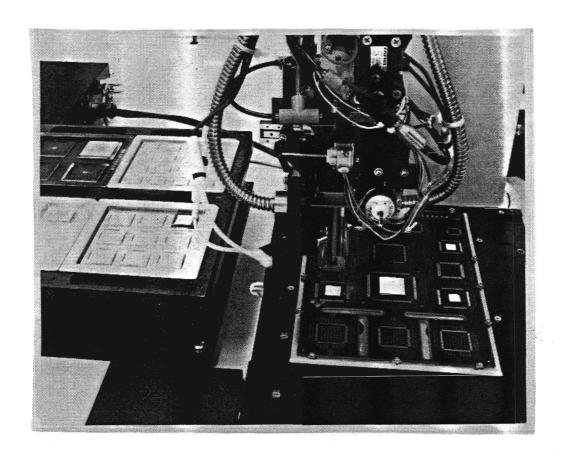
UNCURED ADHESIVE IS 8-12 MILS THICK



PROCESSES AND PROCESS CONTROL (COMPONENT PLACEMENT)

- LEADED DEVICES
 - UTILIZE ROBOTIC PLACEMENT STATION
 - .001" ACCURACY NEEDED FOR 20 -25 MIL PARTS
 - .002" ACCURACY NEEDED FOR 40-50 MIL PARTS
 - Z-AXIS PRESSURE OF 11 POUNDS TO CONTACT ADHESIVE
 - NO X-Y MOVEMENT AFTER PLACEMENT TO PREVENT MOVEMENT DURING ADHESIVE CURE
- LEADLESS DEVICES
 - PICK AND PLACE OR MANUAL PLACEMENT CAN BE USED
 - 25% OVERHANG WILL SELF ALIGN DURING REFLOW

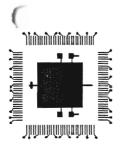




GENERAL ELECTRIC

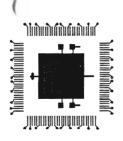
WESTINGHOUSE

MARTIN MARIETTA 89 NEPCON EAST/SD50



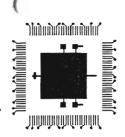
PROCESSES AND PROCESS CONTROL (THERMAL ADHESIVE CURE)

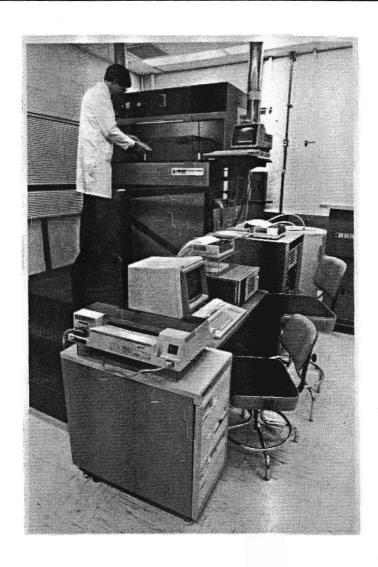
- 150°C FOR 1 HOUR
- MUST ELIMINATE X-Y MOVEMENT
- Z-AXIS PRESSURE ONLY
- NITROGEN ATMOSPHERE TO PREVENT PWB OXIDATION
- COMPLETE CURE INSURES FULL CROSS-LINKING OF POLYMER



PROCESSES AND PROCESS CONTROL (REFLOW)

- VAPOR PHASE SOLDERING SYSTEM
 - COMPUTER CONTROL SYSTEM
 - CAPABILITY FOR RAPID COOLING
- PROFILE TAILORED TO FLUX OR SOLDER PASTE USED
- FIXTURE PWB TO PREVENT WARPING

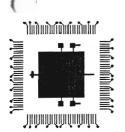


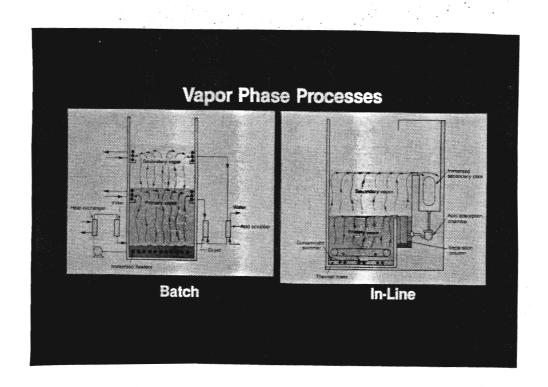


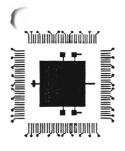
GENERAL ELECTRIC

WESTINGHOUSE

MARTIN MARIETTA
89 NEPCON EAST/SD53



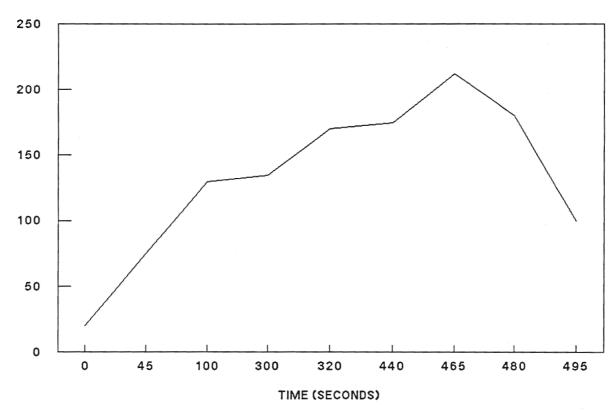




PROCESSES AND PROCESS CONTROL (REFLOW)

TYPICAL VAPOR PHASE REFLOW PROFILE:

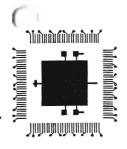




GENERAL ELECTRIC

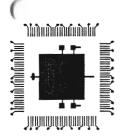
WESTINGHOUSE

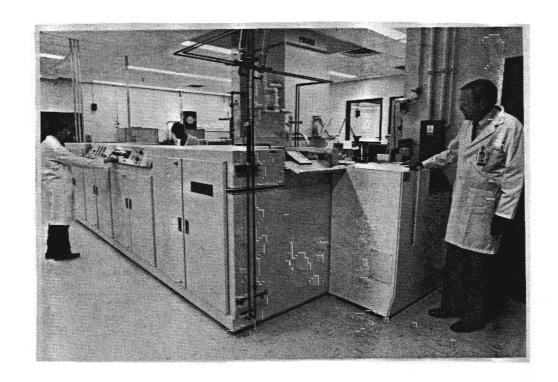
MARTIN MARIETTA 89 NEPCON EAST/SD55

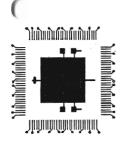


PROCESSES AND PROCESS CONTROL (CLEANING)

- IN-LINE SYSTEM
 - CONTROLLED BELT SPEED
 - CONTROLLED SPRAY PRESSURES
- SOLVENT STILL TO REPLENISH SOLVENT WHEN DIRTY
- TOP SPRAYS AT HIGHER PRESSURE TO PREVENT PWBs FROM FLOATING
- CLEAN WITHIN 10 MINUTES OF SOLDERING WHILE FLUX IS STILL WARM

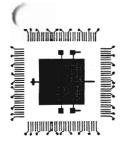




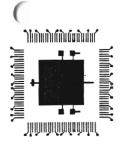


PROCESSES AND PROCESS CONTROL (CLEANLINESS TESTING)

- DO NOT HANDLE PWA BETWEEN CLEANING AND CLEANLINESS TESTING WITHOUT GLOVES OR FINGER COTS
- ICOM 3000 PROVIDES 40 PSI SPRAYS FOR "MORE ACCURATE" TEST RESULTS
- PWAs PASSING OMEGAMETER WILL STILL FAIL ICOM IF DIRTY
- CAN ALSO FUNCTION AS CLEANING OPERATION
- CALIBRATION OF TEST SOLUTION EVERY 4 HOURS
- SET TEST TIME TO 3 MINUTES
- INSURE CORRECT PWA SURFACE AREA IS INPUT TO TESTER

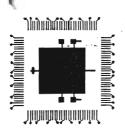


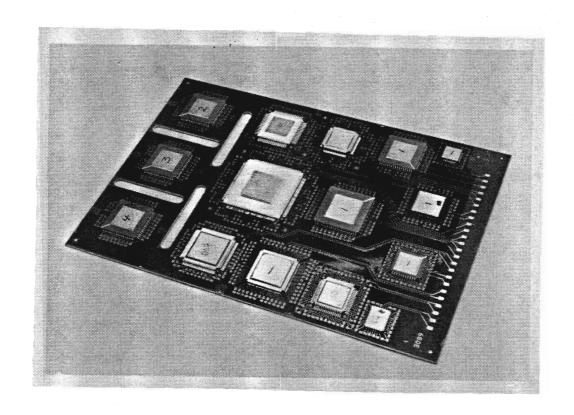


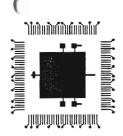


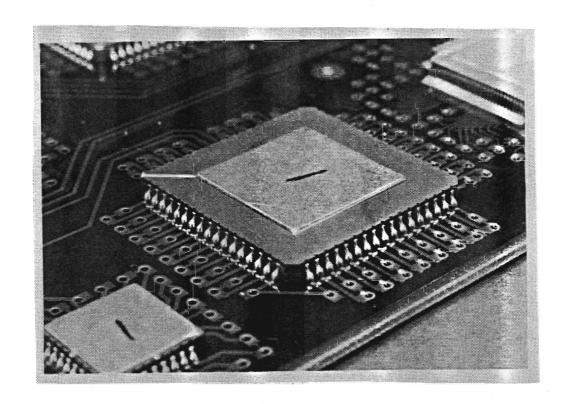
PROCESSES AND PROCESS CONTROL (CHARACTERIZATION)

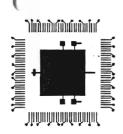
- USED TO COMPARE PROCESS VARIABLES
- MEASURES
 - LCC HEIGHT OFF PWB SURFACE
 - LCC JOINT GEOMETRY
 - LEADED JOINT GEOMETRY
- CHARACTERIZATION SHOULD BE DONE BY SAME INDIVIDUAL OR PEOPLE TRAINED BY SAME INSTRUCTOR

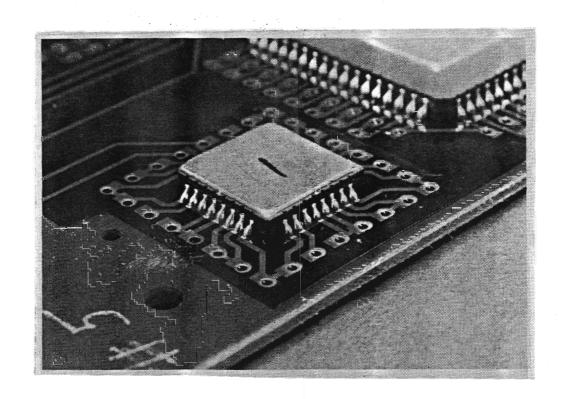


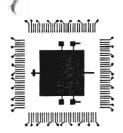


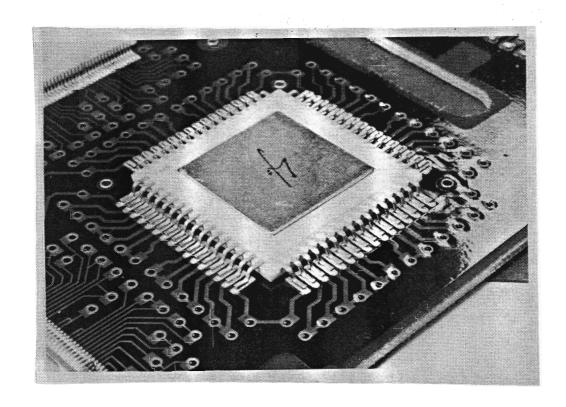


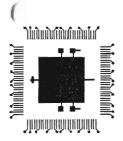


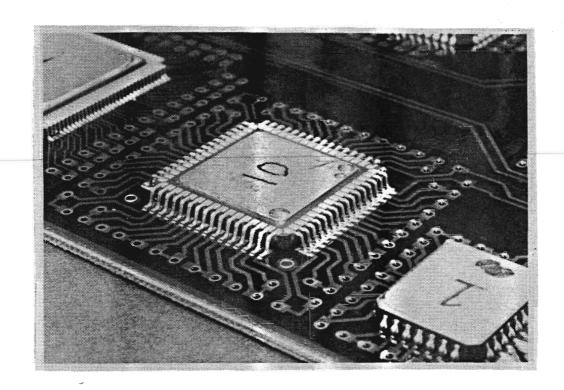


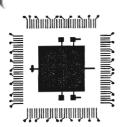


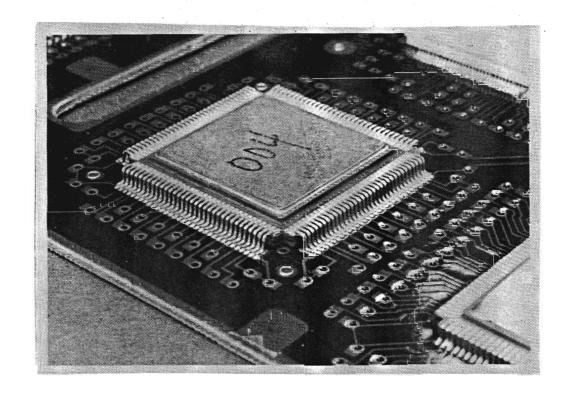


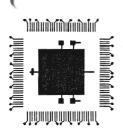


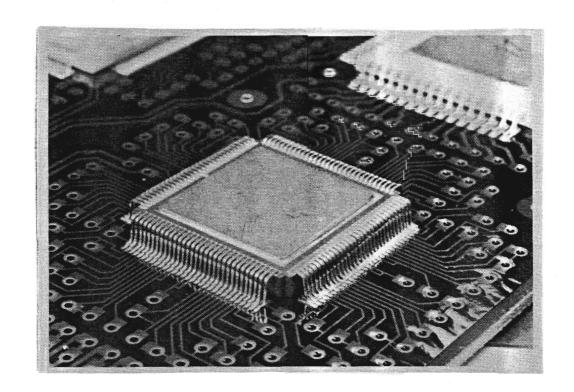


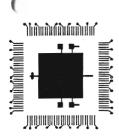






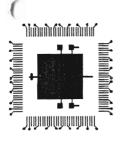






PROCESSES AND PROCESS CONTROL (INSPECTION)

- OPTICAL INSPECTION TO APPLICABLE MILITARY REQUIREMENTS
- DETERMINE ELECTRICAL MALFUNCTIONS
- IDENTIFY TYPES AND QUANTITIES OF DEFECTS



PROCESSES AND PROCESS CONTROL (INSPECTION)

TYPICAL DEFECTS

NON-SOLDERED CONNECTION

BRIDGING

COLD SOLDER JOINT

FRACTURED OR DISTURBED JOINT

INSUFFICIENT SOLDER

EXCESSIVE SOLDER, LEAD NOT DISCERNIBLE • LEAD TOO HIGH

POOR WETTING

SOLDER SPLATTERING/BALLS

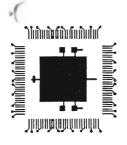
PITS, PINHOLES, VOIDS

- DEWETTING OF SOLDER CONNECTION AREA(S)
- SOLDER NOT SHINY AND SMOOTH
- FLUX RESIDUES, OIL, GREASE ON ASSEMBLY
- CONTAMINANTS IN SOLDER CONNECTION
- EXPOSED COPPER
- COMPONENT/LEAD MISREGISTRATION
- COMPONENT NOT LEVEL
- OTHER (SPECIFY ON DOCUMENTATION)

GENERAL ELECTRIC

WESTINGHOUSE

MARTIN MARIETTA 89 NEPCON EAST/SD69



PROCESSES AND PROCESS CONTROL (CONFORMAL COAT)

- BAKE 1-4 HOURS @ 250°F +-18°F PRIOR TO COATING
- COAT WITHIN 24 HOURS OF BAKE OR STORE IN NITROGEN
- MASK AREAS TO REMAIN UNCOATED AREAS AFTER BAKING
- SPRAY COATING IN MULTIPLE APPLICATIONS TO ACHIEVE .002" +-.001" THICKNESS
- CURE FOR 1 HOUR AT ROOM TEMPERATURE FOLLOWED BY 60 +- 20 MINUTES @ 150°F +- 12°F



PROCESSES AND PROCESS CONTROL (TEST)

- ENVIRONMENTAL
 - THERMAL CYCLING
 - VIBRATION
- ELECTRICAL

Text: NEWFILE

Portfolio List: Page 1 of 2

Topic	File Path	DRW Filename	Print
1:INTRO SLIDE	C:\FL\NEPCON\	SD01.DRW	yes_
2:GOALS OF PROGRAM	C:\FL\NEPCON\	SD02.DRW	yes_
3:THERMAL CYCLES (BACKUP SLIDE)	C:\FL\NEPCON\	SD03.DRW	yes_
4:PWB PICTURE (BARE BOARD)	C:\FL\NEPCON\	SD04.DRW	yes_
5:MATERIALS/EQUIPMENT DISCLAIMER		SD05.DRW	yes_
6:VARIABLES CONSIDERED IN PROCES		SD06.DRW	yes_
7: PROCESS FLOWCHART - PREFORMS	C:\FL\NEPCON\	SD07.DRW	yes_
8:PROCESS FLOWCHART - STENCILS	C:\FL\NEPCON\	SD08.DRW	yes_
9:MATERIALS	C:\FL\NEPCON\	SD09.DRW	yes_
10:EQUIPMENT FLOWCHART	C:\FL\NEPCON\	SD10.DRW	yes_
11:MATERIALS	C:\FL\NEPCON\	SD11.DRW	yes_
12: SOLDER PASTE	C:\FL\NEPCON\	SD12.DRW	yes_
13: SOLDER PREFORMS	C:\FL\NEPCON\	SD13.DRW	yes_
14: FLUX	C:\FL\NEPCON\	SD14.DRW	yes_
15: ADHESIVES	C:\FL\NEPCON\	SD15.DRW	yes_
16: REFLOW FLUIDS	C:\FL\NEPCON\	SD16.DRW	yes_
17: CLEANING SOLVENTS	C:\FL\NEPCON\	SD17.DRW	yes_
18:ASSEMBLY PROCESSES	C:\FL\NEPCON\	SD18.DRW	yes_
19: COMPONENT PREP	C:\FL\NEPCON\	SD19.DRW	yes_
20: PRETINNING	C:\FL\NEPCON\	SD20.DRW	yes_
21: TINNING POT PICTURE	C:\FL\NEPCON\	SD21.DRW	yes_
22: LEAD FORMING	C:\FL\NEPCON\	SD22.DRW	yes_
?3: FORMING DIE PICTURE	C:\FL\NEPCON\	SD23.DRW	yes_
-24: FORMED 124 I/O PICTURE	C:\FL\NEPCON\	SD24.DRW	yes_
25: PREFORMS	C:\FL\NEPCON\	SD25.DRW	yes_
26: PROCESS PICTURES	C:\FL\NEPCON\	SD26.DRW	yes_
27: PROCESS PICTURES	C:\FL\NEPCON\	SD27.DRW	yes_
28: PROCESS PICTURES	C:\FL\NEPCON\	SD28.DRW	yes_
29: PROCESS PICTURES	C:\FL\NEPCON\	SD29.DRW	yes_
30: PROCESS PICTURES	C:\FL\NEPCON\	SD30.DRW	yes_
31: ADVANTAGES	C:\FL\NEPCON\	SD31.DRW	yes_
32: DISADVANTAGES	C:\FL\NEPCON\	SD32.DRW	yes_
33: PWB PREP	C:\FL\NEPCON\	SD33.DRW	yes_
34: THICK PLATE	C:\FL\NEPCON\	SD34.DRW	yes_
35: MOISTURE BAKE-OUT	C:\FL\NEPCON\	SD35.DRW	yes_
36: OVEN PICTURE	C:\FL\NEPCON\	SD36.DRW	yes_
37: STENCIL PRINTING	C:\FL\NEPCON\	SD37.DRW	yes_
38: SCREEN PRINTER PICTURE	C:\FL\NEPCON\	SD38.DRW	yes_
39: PROCESS PICTURES	C:\FL\NEPCON\	SD39.DRW	yes
40: PROCESS PICTURES	C:\FL\NEPCON\	SD40.DRW	yes_
41: PROCESS PICTURES	C:\FL\NEPCON\	SD41.DRW	yes_
42: PROCESS PICTURES	C:\FL\NEPCON\	SD42.DRW	yes
43: ADHESIVES	C:\FL\NEPCON\	SD43.DRW	yes_
44: LCC STANDOFF ADHESIVE	C:\FL\NEPCON\	SD44.DRW	yes_
45: EFD DISPENSER PICTURE	C:\FL\NEPCON\	SD45.DRW	yes_
46: UV CURING SYSTEM	C:\FL\NEPCON\	SD46.DRW	yes_
47: LEADED THERMAL ADHESIVE	C:\FL\NEPCON\	SD47.DRW	yes_
48: ADHESIVE PREFORM SIZES	C:\FL\NEPCON\	SD48.DRW	yes_
9: COMPONENT PLACEMENT	C:\FL\NEPCON\	SD49.DRW	yes_
50: ADEPT ROBOT PICTURE	C:\FL\NEPCON\	SD50.DRW	yes_
51: ADHESIVE CURE	C:\FL\NEPCON\	SD51.DRW	yes_
52: REFLOW	C:\FL\NEPCON\	SD51.DRW	yes_
53: VAPOR PHASE PICTURE	C:\FL\NEPCON\	SD53.DRW	_
JJ. VALOR FIRDE FICTORE	_ C. /LD/MDECOM /		yes_

Text: NEWFILE

Portfolio List: Page 2 of 2

SAPOR PHASE CROSS SECTION C.\FI_\NEPCON SD54.DRW yes		Topic	File Path	DRW Filename	Print
55: VAPOR PHASE PROFILE	54.				
Section Sect					_
57: DETREX PICTURE C:\FL\NEPCON\ SD57.DRW Yes					_
S8					_
SOS TCOM 3000 PICTURE C:\FL\NEPCON\ SDS DRW Yes					_
60: CHARACTERIZATION					_
61: PWB PICTURE (COMPLETED) 62: 68 I\0 .050 PITCH LCC 63: 32 I\0 .040 PITCH LCC 63: 32 I\0 .040 PITCH LCC 65: 64 I\0 .050 PITCH LEADED 65: 64 I\0 .050 PITCH LEADED 65: 64 I\0 .050 PITCH LEADED 65: 64 I\0 .025 PITCH LEADED 66: 132 I\0 .025 PITCH LEADED 67: 124 I\0 .020 PITCH LEADED 68: INSPECTION 69: INSPECTION 69: INSPECTION 69: INSPECTION 69: INSPECTION 60: C:\FL\NEPCON\ 61: TEST 61: TEST 62: \FL\NEPCON\ 63: INSPECTION 64: 64 I\0 .020 PITCH LEADED 65: 64 I\0 .020 PITCH LEADED 66: INSPECTION 67: C:\FL\NEPCON\ 67: C:\FL\NEPCON\ 68: INSPECTION 69: INSPECTION 69: INSPECTION 69: INSPECTION 60: C:\FL\NEPCON\ 60: INSPECTION 60: C:\FL\NEPCON\ 60: INSPECTION 60: INS			· · · · · · · · · · · · · · · · · · ·		
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67: 124 I\0 .020 PITCH LEADED C:\FL\NEPCON\ SD67.DRW yes 68: INSPECTION C:\FL\NEPCON\ SD68.DRW no 69: INSPECTION - DEFECTS C:\FL\NEPCON\ SD69.DRW no 70: CONFORMAL COAT C:\FL\NEPCON\ SD70.DRW no 71: TEST C:\FL\NEPCON\ SD70.DRW no 72:					
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69: INSPECTION - DEFECTS C:\FL\NEPCON SD69.DRW no					yes_
70: CONFORMAL COAT					no
71: TEST					no
72: no 73: no 74: no 75: no 76: no 77: no 78: no 79: yes 80: yes 81: yes 82: yes 83: yes 84: yes 85: yes 86: yes 87: yes 88: yes 90: yes 91: yes 92: yes 93: yes 94: yes 95: yes 97: yes 98: yes 99: yes					no
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74: no 75: no 76: no 77: no 78: no 79: yes 80: yes 81: yes 82: yes 83: yes 84: yes 85: yes 86: yes 87: yes 89: yes 90: yes 91: yes 92: yes 93: yes 94: yes 95: yes 96: yes 97: yes 98: yes 99: yes	72:				no
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Military nD 2000)

1 Raby, Soldering tional Inc.

Course e are accustomed to

Ider joints and elecpurely for cosmetnetics must be ur emphasis must ect, "Integrity". We doesn't look good. Justry with the ratior cosmetics and to rison of, and new inspection for

egrity and what

if cosmetics are ng and/or just a

uch indiscriminate ints within our iminate touchup is t that the solder does not look like ne picture in our pecification. illy serves to tion rather than ı it can do internal ge to our circuit nis costs money.

II. Course Content

We will begin with the cosmetic requirements and how/why they originated. We will then progress through new rationale and test data to show the solder joint inside.

What it looks like on the outside when it is good inside and commence a philosophy change in inspection criteria.

The program will be comprised of slides and photographs of the external solder joint, microsections of good, bad. and marginal joints. There will also be presented pull test data and thermal fatigue data and resulting microsections. It is planned that this data will then be presented to the industry in different forms of educational formats in order to upgrade the knowledge of our industry solder experts.

III. Who Should Attend This Course?

This session is most likely to appeal to and be attended by the facility soldering guru; manufacturing/quality engineer, process engineer, inspection supervisor and inspectors, as well as managers of the assembly line.

PAC 9

Advanced Design/Manufacturing Techniques for High Speed Digital Processing

Course Leader: Dr. Gail Love, Technical Director, Martin Marietta Missile Systems

I. Objectives of the Course

This course will cover the latest design and manufacturing techniques that are being employed in the design of high speed digital electronic circuits/ assemblies. The material to be presented has been developed under the Manufacturing Technology For Advanced Data/Signal Processing (AS/SP) Program.

This will be the first time that the data generated on the AD/SP Program has been taught to the general public. This course will concentrate on providing the attendees with the fundamental design equation, material selection rationale and processes for implementing high speed digital electronic circuits.

II. Course Content

The course is divided into three topic areas. Design: PWB layout; high speed electrical design; thermal considerations; reliability. Materials: Material selection; material specifications; testing and control. Processing: PWB processes/process control; PWA processes/process control.

Emphasis will be placed on presenting the material in such a way that the interrelationships between these key technical areas are clearly understood.

III. Who Should Attend This Course?

This course should be attended by those individuals who are directly involved with the design, materials,

and/or processing of advanced electronic circuits. It is intended that those who attend this course will be able to use the information presented as a teaching aid within their own facilities.

WEDNESDAY 9:00 a.m.

June 14, 1989

WORKSHOP 3

Beyond SMT-Fine Pitch Technology (FPT)

Course Leader: Phil Marcoux, President, **PPM Associates**

I. Objectives of the Course

This course will introduce potential users to the new design and assembly demands of a new breed of high lead count, lower cost IC packages. These packages known under various names such as TAB, PQFP, VSOIC and Tapepak are generally characterized by surface attachable leads whose pitches are 0.025" or less center to center.

II. Course Content

This course includes a description of the package types. Cost performance and size advantages will be reviewed with emphasis on the cost situation that differs significantly from the early SMT period. The course will conclude with a discussion of the design and board assembly requirements and suggestions of how to minimize capital expense and extra assembly problems.

III. Who Should Attend This Course?

Design and manufacturing engineers, managers and purchasing personnel interested in preparing for the next evolution in packaging and assembly technology.

SESSION 19

Emerging MLB SMT Construction Strategies for the 90's

Chairman: William Teat, Engineering Manager, Motorola Inc.

"Process Technology for Fine-Line Controlled Impedance Printed Circuit Boards", Tony Sweet, Psi Star "Performance Benefits of Resin Systems Beyond FR4", Richard Hein, Norplex/Oak "Solder Mask Testing for Hi-Rel Printed Circuit Boards", Frank Juskey, Motorola Inc.

"Blind Via-A Useful Tool for High Density SMT Realization", Alan Beekman, Futura Circuits Corporation "Integramount, an Alternative to Solder Finish", Bob Davenport and Tom Weaver, Printed Wiring Inc.

SESSION 20

VXIbus ATE Systems

Chairman: David Haworth, VXI Program Manager, Tektronix, Inc.

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SESSION

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Project

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NEPCON EAST '89

SESSION PROPOSAL

Nepcon East '89
Bayside Exposition Center
Boston, Massachusetts
June 12 - 15, 1989

Proposed Chairman's Name: Gail F. Love

Company Address: Martin Marietta Corporation

Martin Marietta Missile Systems

P.O. Box 555837

City/State/Zip: Orlando, Florida 32855-5837

Telephone, FAX: (407)356-5706, (407)356-3393

1. Proposed Topic: Advanced Design/Manufacturing Techniques

For High Speed Digital Processing

2. Focus Of Proposed Topic:

This one-day professional advancement course will cover the latest design and manufacturing techniques that are being employed in the design of high speed digital electronic circuits/assemblies. The material to be presented has been developed under the Manufacturing Technology For Advanced Data/Signal Processing (AD/SP) Program, Contract F33615-85-C-5065, funded by the Materials Laboratory of Wright-Patterson Air Force Base in Dayton, Ohio.

The primary purpose of this session is to make the data developed during the program available to the technical community in a training type environment so that the attendee's will be able to learn how to implement the technology into their own electronic systems/subsystems.

This will be the first time that the data generated on the AD/SP Program has been taught to the general public. The course will concentrate on providing the attendee's with the fundamental design equations, material selection rationale, and processes for implementing high speed digital electronic circuits.

3. Who Should Attend:

This course should be attended by those individuals who are directly involved with the design, materials, and/or processing of advanced electronic circuits. It is intended that those who attend this course will be able to use the information presented as a teaching aide within their own facilities.

4. Planned Technical Composition:

The course will be divided into three topics:

- A) Design
- B) Materials
- C) Processing

Emphasis will be placed on presenting the material in such a way that the interrelationships between these three key technical areas are clearly understood.

5. Proposed Speakers And Planned Technical Papers:

Subject	<u>Paper</u>	Spe	eaker	<u>Co</u>	Tir	<u>ne</u>
Overview		G.	Love	MM	15	Min
Design	PWB Layout High Speed Electrical Design		Love Canright	MM MM		Min Hr.
	Thermal Considerations Reliability		Brzozowski Love	WEST MM		Min Min
Materials	Material Selection Material Specifications, Testing and Control		Brzozowski Pattison	WEST MM		Min Min
Processing	PWB Processes/Process	J.	Chamblin	MM	1	Hr
	Control PWA Processes/Process Control	S.	Dahne	WEST	1	Hr